

# Characterization of tunneling and freecarrier screening in coupled asymmetric GaN/AIGaN quantum discs

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commercial applications (e.g. solid-state lighting, HD-DVD) •FUTURE: Novel devices



•SCOPE: Systematic study of carrier tunneling and free-carrier screening in coupled asymmetric GaN Q-discs separated by AlGaN barriers •METHOD: Combination of experimental and computational methods

- •Photoluminescence (PL) spectroscopy •Time-resolved (TR-) and time-integrated (TI-)
- Multi-band k.p computational modeling •nextnano<sup>3</sup>

## •MOTIVATION:

 Commercial importance of III-N materials •Free-carrier screening not observed for nanocolumn devices

\*Tunneling and screening in such structures has been suggested previously [1] and could play an important role in future devices.

ve gained interest in application for blue/ultra-ess desirable properties such as low defec nt effects and can be produced using com anocolumns an attractive basis for novel quantu tum dots in nanopillar cavities for quantum infor n processing [2]) tum discs (O-discs) are quantum well like structures grown at the tip of GaN nanocolumns are as and demonstrate lateral confinement



e GaN nanocolumn sample and the GaN Q-disc sample were g am epitaxy on a Si(111) substrate without any buffer layer. The formed under N-rich conditions. The Ga flux was controlled to a rr, which is approximately ten times smaller than that used for Ga d flow rate of the N plasma source were 350 W and 2.0 sccm, re 750 °C was used

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The hexagonal GaN nanocolumns exhibit various diameters ranging from 50 to 120 nm, with an average diameter of 100 nm and a density of 1x10° cm<sup>-2</sup>.



### **TI-PL Results**

- Optical non-linearity: With increasing excitation, DA peak grows faster than DB peak. This is more evident in the 2 nm barrier sample
- •Observed in asymmetric quantum well systems and associated with *carrier tunneling* [3] •First indication of electron/holes tunneling: DB→DA

•TR-PL Results

S nm barrier sample: DA lifetime decreased from 510 to 400 ps (for 0.02 to 1.4 mW at focus)
DB lifetime: Varied from ~480 to 380 ps (0.02 to 1.4 mW) in both the 2 and 8nm samples





- Source: Excited (e.g. by photo-excitation) electrons/hole Effect: Screens the built-in piezo-electric field → Increased electron-hole overlap → Decreased lifetime Enhancement of free-carrier screening
- ource: Electrons/Holes tunneling from DB→DA • *Effect:* Free-carrier screening (decreases with barrier thickness) effect is enhanced
- series of TR-PL measurements (taken at 2nm intervals) dicate that the majority of interactions occur in the first 500 ps I. Here the DA peak blue-shifted (gain of free-carriers).

•Free-carrier screening in asymmetric GaN/AIGaN Q-discs have been characterized. It consists of:

- Photo-excited electrons/holes
- •Electron/Hole tunneling (DB  $\rightarrow$  DA)

•Tunneling leads to an enhancement of the screening in DA, as it provides additional free-carriers

- •Enhancement depends on the barrier thickness (i.e. tunneling)
- •Predicted by computer modeling (nextnano<sup>3</sup>)
- •Previously only observed in quantum wells (i.e. not in nano-scale devices such as nanocolumns or Q-discs)
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